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INFORMATION	LOSURE STATEMENT
BY APP	PLICANT

Attorney Docket Number	1011-67625-01
Application Number	10/777,443
Filing Date	February 10, 2004
First Named Inventor	Rajski
Art Unit	Unknown
Examiner Name	Unknown

## **U.S. PATENT DOCUMENTS**

NOTE: If this application was filed after June 30, 2003, copies of United States patents and United States published patent applications do not have to be provided to the Patent Office. This requirement of 37 C.F.R. § 1.98(a)(2)(i) has been waived by the United States Patent and Trademark Office pursuant to the Official Gazette Notice on August 5, 2003 (1276 OG 55).

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EXAMINER SIGNATURE:	DATE CONSIDERED: 7/21/04
	CONSIDERED. 1 1 1 ( 6)

<sup>\*</sup> Examiner: Initial if reference considered, whether or not in conformance with MPEP 609. Draw line through cite if not in conformance and not considered. Include copy of this form with next communication to applicant.

		Attorney Docket Number	1011-67625-01
		Application Number	10/777,443
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		First Named Inventor	Rajski
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